

Solid Tantalum Chip Capacitors MICROTAN™ Low ESR, Leadframeless Molded



FEATURES

- 0603 and 0805 footprint
- Lead (Pb)-free face-down terminations
- 8 mm tape and reel packaging available per EIA-481-1 and reeling per IEC 286-3 7" [178 mm] standard
- Low ESR



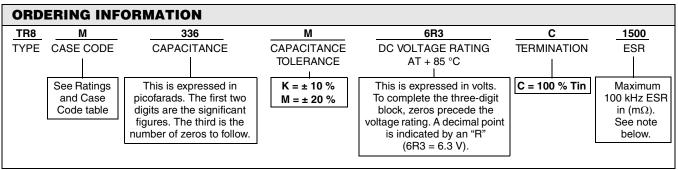
RoHS COMPLIANT GREEN (5-2008)

PERFORMANCE CHARACTERISTICS

Operating Temperature: - 55 °C to + 85 °C

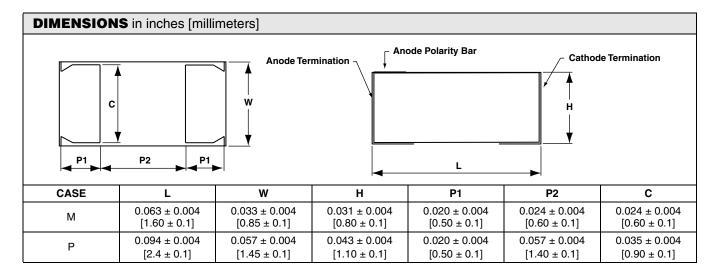
(To + 125 °C voltage derating)

Capacitance Range: 1 μ F to 220 μ F Capacitance Tolerance: \pm 20 % standard Voltage Range: 4 WVDC to 16 WVDC



Note

We reserve the right to supply higher voltage ratings and tighter capacitance tolerance capacitors in the same case size. Voltage substitutions will be marked with the higher voltage rating. The EIA and CECC standars for low ESR solid tantalum chip capacitors, allow delta ESR of 1.25 times the data sheet limit after mounting.





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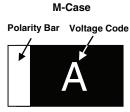
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Voltage Capacitance Code Code

P-Case

RATINGS AND CASE CODES							
μF	2.5 V	4 V	6.3 V	10 V	16 V		
1.0					М		
2.2							
3.3							
4.7					M*		
6.8							
10			М	М			
15				М			
22			М				
33		М	М				
47		М		P*			
220		P*					

MARKING



	Cap, μF	Code
	33	n
1	47	S
	68	w
	100	Ā
	150	

220

Polarity Bar

Volts	Code
4	G
6.3	J
10	Α
16	С
20	D
25	E

Note

^{*} Preliminary values, contact factory for availability.

STANDARD RATINGS							
CAPACITANCE (µF)	CASE CODE	PART NUMBER	MAX. DC LEAKAGE AT + 25 °C (μΑ)	MAX. DF AT + 25 °C (%)	MAX. ESR AT + 25 °C 100 kHz (Ω)	MAX. RIPPLE 100 kHz I _{rms} (A)	∆C/C* (%)
		4 WVDC AT + 85 °C, SU	RGE = 5.2 V	2.7 WVDC AT -	+ 125 °C, SURGE	= 3.4 V	
33	М	TR8M336M004C1500	2.6	15	1.5	0.129	± 20
47	М	TR8M476M004C1500	3.8	20	1.5	0.129	± 30
220	Р	TR8P227M004C1000	17.6	30	1.0	0.212	± 30
		6.3 WVDC AT + 85 °C ,	SURGE = 8 V.	. 4 WVDC AT	+ 125 °C, SURGE	= 5 V	
10	М	TR8M106M6R3C2000	0.6	8.0	2.0	0.112	± 10
22	М	TR8M226M6R3C1500	2.8	20	1.5	0.129	± 15
33	М	TR8M336M6R3C1500	4.2	30	1.5	0.129	± 30
		10 WVDC AT + 85 °C, \$	SURGE = 13 V.	. 7 WVDC AT	+ 125 °C, SURGE	= 8 V	
10	М	TR8M106M010C2000	1.0	20	3.0	0.112	± 15
15	М	TR8M156M010C3000	1.5	20	3.0	0.091	± 20
47	Р	TR8M476M010C0800	4.7	22	0.8	0.237	± 20
		16 WVDC AT + 85 °C, S	URGE = 20 V	10 WVDC AT	+ 125 °C, SURGE	= 12 V	•
1	М	TR8M105M016C9500	0.5	6.0	9.5	0.050	± 15
4.7	М	TR8M475M016C4000	0.8	8.0	4.0	0.079	± 15

Note

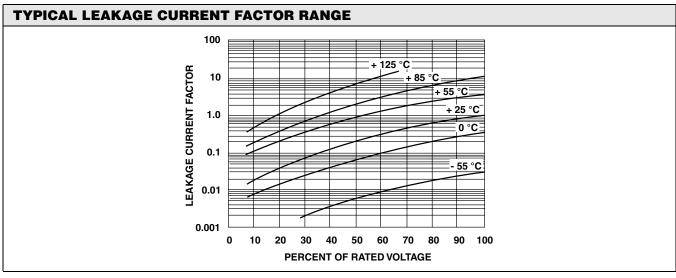
^{*} See Performance Characteristics tables, page 41.

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CAPACITORS PERFORMANCE CHARACTERISTICS

ITEM	PERFORMANCE CHARACTERISTICS					
Category Temperature Range	- 55 °C to + 85 °C (to + 12	5 °C with voltage derating)				
Capacitance Tolerance	± 20 %, ± 10 % (at 120 Hz) 2 V _{rms} at + 25 °C using a	capacitance bridge			
Dissipation Factor (at 120 Hz)		s Table. Tested via bridge r				
ESR (100 kHz)	Limits per Standard Rating	s Table. Tested via bridge r	nethod, at 25 °C, 100 kHz.			
Leakage Current	After application of rated voltage applied to capacitors for 5 minutes using a steady source of power with					
	1 kΩ resistor in series with	the capacitor under test, lea	akage current at 25 °C is not	more than described in.		
	See graph below for the ap	propriate adjustment factor	: .			
Reverse Voltage	Capacitors are capable of	withstanding peak voltages	in the reverse direction equa	al to: 10 % of the DC		
	5 % of the DC rating at + 8	5 °C				
	Vishay does not recomme	nded intentional or repetitive	e application of reverse volta	age		
Temperature Derating	If capacitors are to be used	d at temperatures above + 2	25 °C, the permissible rms ri	pple current or voltage		
Temperature Derating	If capacitors are to be used 1.0 at + 25 °C 0.9 at + 85 °C	d at temperatures above + 2	25 °C, the permissible rms ri	pple current or voltage		
Temperature Derating Operating Temperature	1.0 at + 25 °C		25 °C, the permissible rms ri + 125 °C	5		
, ,	1.0 at + 25 °C 0.9 at + 85 °C			5		
, ,	1.0 at + 25 °C 0.9 at + 85 °C + 85 °C	RATING	+ 125 °C	RATING		
	1.0 at + 25 °C 0.9 at + 85 °C + 85 °C WORKING VOLTAGE	RATING SURGE VOLTAGE	+ 125 °C WORKING VOLTAGE	RATING SURGE VOLTAGE		
, ,	1.0 at + 25 °C 0.9 at + 85 °C + 85 °C WORKING VOLTAGE	RATING SURGE VOLTAGE 5.2	+ 125 °C WORKING VOLTAGE 2.7	RATING SURGE VOLTAGE 3.4		
, ,	1.0 at + 25 °C 0.9 at + 85 °C + 85 °C WORKING VOLTAGE 4 6.3	RATING SURGE VOLTAGE 5.2 8	+ 125 °C WORKING VOLTAGE 2.7 4	RATING SURGE VOLTAGE 3.4 5		
, ,	1.0 at + 25 °C 0.9 at + 85 °C + 85 °C WORKING VOLTAGE 4 6.3 10	RATING SURGE VOLTAGE 5.2 8 13	+ 125 °C WORKING VOLTAGE 2.7 4 7	### RATING SURGE VOLTAGE		
, ,	1.0 at + 25 °C 0.9 at + 85 °C + 85 °C WORKING VOLTAGE 4 6.3 10 16	RATING SURGE VOLTAGE 5.2 8 13 20	+ 125 °C WORKING VOLTAGE 2.7 4 7 10	RATING SURGE VOLTAGE 3.4 5 8 12		
	1.0 at + 25 °C 0.9 at + 85 °C + 85 °C WORKING VOLTAGE 4 6.3 10 16 20	8 13 20 26	+ 125 °C WORKING VOLTAGE 2.7 4 7 10 13	RATING SURGE VOLTAGE 3.4 5 8 12 16		



Notes

- At + 25 °C, the leakage current shall not exceed the value listed in the Standard Ratings Table.
- At + 85 °C, the leakage current shall not exceed 10 times the value listed in the Standard Ratings Table.
- At + 125 °C, the leakage current shall not exceed 12 times the value listed in the Standard Ratings Table.

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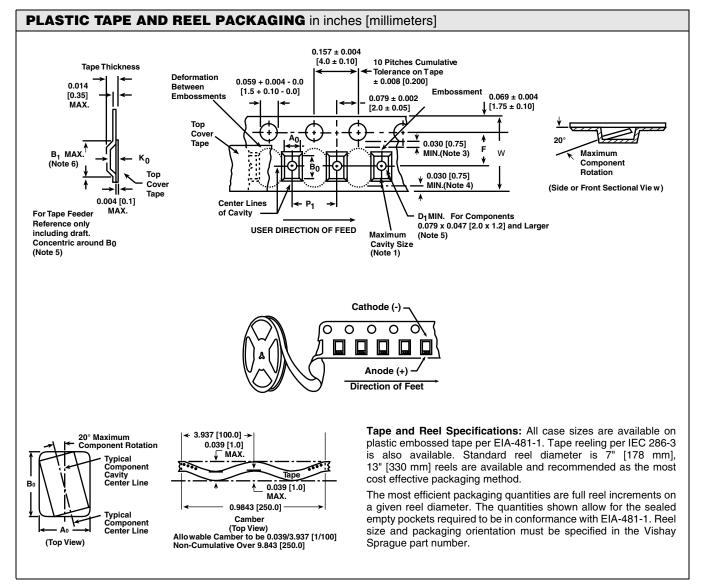
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ENVIRONMENTAL PERFORMANCE CHARACTERISTICS						
ITEM	CONDITION	POST TEST PERFORMANCE				
Life Test at + 85 °C	1000 hours application of rated voltage at 85 °C with a 3 Ω series resistance, MIL-STD 202G Method 108A	Capacitance Change Refer to Standard Ratings Table Dissipation Factor Not to exceed 150 % of initial Leakage Current Not to exceed 200 % of initial				
Humidity Tests	At 40 °C/90 % RH 500 hours, no voltage applied. MIL-STD 202G Method 103B	Capacitance Change Refer to Standard Ratings Table Dissipation Factor Not to exceed 150 % of initial Leakage Current Not to exceed 200 % of initial				
Thermal Shock	At - 55 °C/+ 125 °C, 30 minutes each, for 5 cycles. MIL-STD 202G Method 107G	Capacitance Change Refer to Standard Ratings Table Dissipation Factor Not to exceed 150 % of initial Leakage Current Not to exceed 200 % of initial				

MECHANICAL	MECHANICAL PERFORMANCE CHARACTERISTICS					
TEST CONDITION	CONDITION	POST TEST PERFORMANCE				
Terminal Strength	Apply a pressure load of 5 N for 10 \pm 1 seconds horizontally to the center of capacitor side body. AECQ-200 rev. C Method 006	Capacitance Change Refer to Standard Ratings Table Dissipation Factor Initial specified value or less Leakage Current Initial specified value or less				
		There shall be no mechanical or visual damage to capacitors post-conditioning.				
Substrate Bending (Board flex)	With parts soldered onto substrate test board, apply force to the test board for a deflection of 1 mm. AECQ-200 rev. C Method 005	Capacitance Change Refer to Standard Ratings Table Dissipation Factor Initial specified value or less Leakage Current Initial specified value or less				
Vibration	MIL-STD-202G, Method 204D, 10 Hz to 2000 Hz, 20 G Peak	Capacitance Change Refer to Standard Ratings Table Dissipation Factor Initial specified value or less Leakage Current Initial specified value or less				
		There shall be no mechanical or visual damage to capacitors post-conditioning.				
Shock	Mil-Std-202G, Method 213B, Condition I, 100G Peak	Capacitance Change Refer to Standard Ratings Table Dissipation Factor Initial specified value or less Leakage Current Initial specified value or less				
		There shall be no mechanical or visual damage to capacitors post-conditioning.				
Resistance to Solder Heat	At 260 °C, for 10 seconds, reflow	Capacitance Change Refer to Standard Ratings Table Dissipation Factor Not to exceed 150 % of initial Leakage Current Not to exceed 200 % of initial				
		There shall be no mechanical or visual damage to capacitors post-conditioning.				
Solderability	MIL-STD-202G, Method 208H, ANSI/J-Std-002, Test B. Applies only to Solder and tin plated terminations. Does not apply to gold terminations.	There shall be no mechanical or visual damage to capacitors post-conditioning.				
Resistance to Solvents	MIL-STD-202, Method 215D	There shall be no mechanical or visual damage to capacitors post-conditioning.				
Flammability	Encapsulation materials meet UL94 VO with an oxygen index of 32 %.					

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Note:

Metric dimensions will govern. Dimensions in inches are rounded and for reference only.

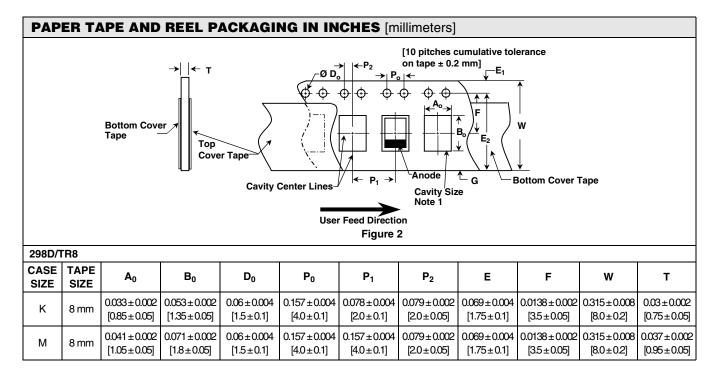
CASE CODE	TAPE SIZE	B ₁ (MAX.)	D ₁ (MIN.)	F	K ₀ (MAX.)	P ₁	w
298D/TR8							
Р	8 mm	0.108 [2.75]	0.039 [1.0]	0.138 ± 0.002 [3.5 ± 0.05]	0.054 [1.37]	0.157 ± 0.004 [4.0 ± 1.0]	0.315 ± 0.0118/- 0.0039 [8.0 ± 0.30/- 0.10]

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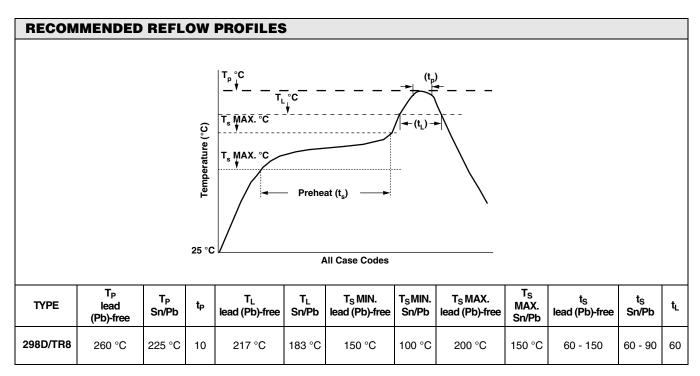
STANDARD PACKAGING QUANTITY						
SERIES	CASE CODE	QTY (PCS/REEL)				
SERIES		7" REEL	13" REEL			
298D/TR8	К	10 000	N/a			
	М	4000	N/a			
	Р	3000	N/a			

RECOMMENDED VOLTAGE DERATING GUIDELI	INES				
STANDARD CONDITIONS: FOR EXAMPLE: OUTPUT FILTERS					
Capacitor Voltage Rating	Operating Voltage				
4.0	2.5				
6.3	3.6				
10	6.0				
16	10				
20	12				
25	15				
35	24				
50	28				
SEVERE CONDITIONS: FOR EXAMPLE: INPUT FILTERS					
Capacitor Voltage Rating	Operating Voltage				
4.0	2.5				
6.3	3.3				
10	5.0				
16	8.0				
20	10				
25	12				
35	15				
50	24				

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POWER DISSIPATION					
CASE CODE MAXIMUM PERMISSIBLE POWER DISSIPATION AT + 25 °C (W) IN FRE					
	К	0.015			
298D/TR8	M	0.025			
	Р	0.045			



PAD DIMENSIONS in inches [millimeters]							
B C							
CASE CODE	CASE CODE A B C D (NOM.) (NOM.)						
298D/TR8	T						
К	K 0.028 [0.70] 0.018 [0.45] 0.024 [0.60] 0.059 [1.50]						
М	M 0.039 [1.00] 0.028 [0.70] 0.24 [0.60] 0.080 [2.00]						
Р	0.063 [1.60]	0.031 [0.80]	0.047 [1.20]	0.110 [2.80]			



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GUIDE TO APPLICATION

 A-C Ripple Current: The maximum allowable ripple current shall be determined from the formula:

$$I_{rms} = \sqrt{\frac{P}{R_{ESR}}}$$

where,

P =

Power dissipation in watts at + 25 °C as given in the table in paragraph number 5

(power dissipation).

R_{ESR} =

The capacitor equivalent series resistance at the specified frequency.

 A-C Ripple Voltage: The maximum allowable ripple voltage shall be determined from the formula:

$$V_{rms} = Z \sqrt{\frac{P}{R_{ESR}}}$$

or, from the formula:

$$V_{rms} = I_{rms} \times Z$$

where,

P =

Power dissipation in watts at + 25 °C as given in the table in paragraph number 5 (power dissipation).

R_{ESR} = The capacitor equivalent series

resistance at the specified frequency.

Z = The capacitor impedance at the specified frequency.

- 2.1 The sum of the peak AC voltage plus the applied DC voltage shall not exceed the DC voltage rating of the capacitor.
- 2.2 The sum of the negative peak AC voltage plus the applied DC voltage shall not allow a voltage reversal exceeding 10 % of the DC working voltage at + 25 °C.
- 3. **Reverse Voltage:** These capacitors are capable of withstanding peak voltages in the reverse direction equal to 10 % of the DC rating at + 25 °C, 5 % of the DC rating at + 85 °C and 1 % of the DC rating at + 125 °C.
- 4. **Temperature Derating:** If these capacitors are to be operated at temperatures above + 25 °C, the permissible rms ripple current or voltage shall be calculated using the derating factors as shown:

	TEMPERATURE	DERATING FACTOR
	+ 25 °C	1.0
	+ 85 °C	0.9
	+ 125 °C	0.4

5. **Power Dissipation:** Power dissipation will be affected by the heat sinking capability of the mounting surface. Non-sinusoidal ripple current may produce heating effects which differ from those shown. It is important that the equivalent I_{rms} value be established when calculating permissible operating levels. (Power Dissipation calculated using + 25 °C temperature rise.)

- 6. **Printed Circuit Board Materials:** Molded capacitors are compatible with commonly used printed circuit board materials (alumina substrates, FR4, FR5, G10, PTFE-fluorocarbon and porcelanized steel).
- 7. Attachment:
- 7.1 **Solder Paste:** The recommended thickness of the solder paste after application is 0.007" ± 0.001" [0.178 mm ± 0.025 mm]. Care should be exercised in selecting the solder paste. The metal purity should be as high as practical. The flux (in the paste) must be active enough to remove the oxides formed on the metallization prior to the exposure to soldering heat. In practice this can be aided by extending the solder preheat time at temperatures below the liquidous state of the solder.
- 7.2 **Soldering:** Capacitors can be attached by conventional soldering techniques; vapor phase, convection reflow, infrared reflow, wave soldering and hot plate methods. The Soldering Profile charts show recommended time/temperature conditions for soldering. Preheating is recommended. The recommended maximum ramp rate is 2 °C per second. Attachment with a soldering iron is not recommended due to the difficulty of controlling temperature and time at temperature. The soldering iron must never come in contact with the capacitor.
- 7.2.1 Backward and Forward Compatibility: Capacitors with SnPb or 100 % tin termination finishes can be soldered using SnPb or lead (Pb)-free soldering processes.
- 8. Cleaning (Flux Removal) After Soldering: Molded capacitors are compatible with all commonly used solvents such as TES, TMS, Prelete, Chlorethane, Terpene and aqueous cleaning media. However, CFC/ODS products are not used in the production of these devices and are not recommended. Solvents containing methylene chloride or other epoxy solvents should be avoided since these will attack the epoxy encapsulation material.
- 8.1 When using ultrasonic cleaning, the board may resonate if the output power is too high. This vibration can cause cracking or a decrease in the adherence of the termination. DO NOT EXCEED 9W/I at 40 kHz for 2 minutes.
- 9. Recommended Mounting Pad Geometries: Proper mounting pad geometries are essential for successful solder connections. These dimensions are highly process sensitive and should be designed to minimize component rework due to unacceptable solder joints. The dimensional configurations shown are the recommended pad geometries for both wave and reflow soldering techniques. These dimensions are intended to be a starting point for circuit board designers and may be fine tuned if necessary based upon the peculiarities of the soldering process and/or circuit board design.



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